TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC7SH04FS

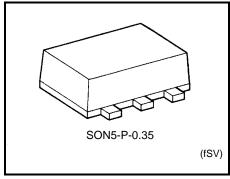
#### **INVERTER**

#### **Features**

High speed:  $t_{pd}$  = 3.8 ns (typ.) at  $V_{CC}$  = 5 V Low power dissipation:  $I_{CC}$  = 2  $\mu$ A (max) at Ta = 25°C High noise immunity:  $V_{NIH}$  =  $V_{NIL}$  = 28%  $V_{CC}$  (min)

5.5V tolerant input.

Wide operating voltage range:  $V_{CC}$  (opr) = 2~5.5 V



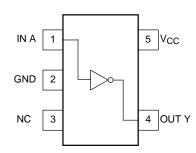
Weight: 0.001 g (Typ.)

#### Marking

H 5

# Type Name

#### Pin Assignment (top view)





## **Maximum Ratings (Ta = 25°C)**

Characteristics	Symbol	Rating	Unit
Supply voltage range	V <sub>CC</sub>	-0.5~7.0	V
DC input voltage	V <sub>IN</sub>	-0.5~7.0	V
DC output voltage	V <sub>OUT</sub>	-0.5~V <sub>CC</sub> + 0.5	V
Input diode current	I <sub>IK</sub>	-20	mA
Output diode current	lok	±20	mA
DC output current	lout	±25	mA
DC V <sub>CC</sub> /ground current	Icc	±50	mA
Power dissipation	PD	50	mW
Storage temperature	T <sub>stg</sub>	-65~150	°C

## Logic Diagram



## **Truth Table**

А	Y
L	Н
Н	L

## **Recommended Operating Conditions**

Characteristics	Symbol	Rating	Unit	
Supply voltage	V <sub>CC</sub>	2.0~5.5	V	
Input voltage	V <sub>IN</sub>	0~5.5	V	
Output voltage	V <sub>OUT</sub>	0~V <sub>CC</sub>	V	
Operating temperature	T <sub>opr</sub>	-40~85	°C	
Input rise and fall time	dt/dv	$0 \sim 100 \; (V_{CC} = 3.3 \pm 0.3 \; V)$	ns/V	
input noe and rail time	ui/uv	$0 \sim 20 \; (V_{CC} = 5 \pm 0.5 \; V)$	113/ V	

## **Electrical Characteristics**

#### **DC Characteristics**

Characteristics Symbol Test Circuit		Test				Ta = 25°C			Ta = -40~85°C		
		Test Condition		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Unit	
High-level input voltage		_		2.0	1.50	_	_	1.50	_	٧	
	_			3.0~ 5.5	V <sub>CC</sub> × 0.7	_	_	V <sub>CC</sub> × 0.7	_		
Low-level input					2.0	_	_	0.50	_	0.50	٧
voltage	V <sub>IL</sub>	_		_		_	_	V <sub>CC</sub> × 0.3	_	V <sub>CC</sub> × 0.3	
			V <sub>IN</sub> = V <sub>IL</sub>	I <sub>OH</sub> = -50 μA	2.0	1.9	2.0	_	1.9	_	V
					3.0	2.9	3.0	_	2.9	_	
High-level output voltage	Voн	_			4.5	4.4	4.5	_	4.4	_	
				I <sub>OH</sub> = -4 mA	3.0	2.58	_	_	2.48	_	
				I <sub>OH</sub> = -8 mA	4.5	3.94	_	_	3.80	_	
Low-level output voltage					2.0	_	0.0	0.1	_	0.1	
		V <sub>IN</sub> =	$I_{OL} = 50 \mu A$	3.0	_	0.0	0.1	_	0.1	V	
	_			4.5	_	0.0	0.1	_	0.1		
			- 111	I <sub>OL</sub> = 4 mA	3.0	_	_	0.36	_	0.44	
				I <sub>OL</sub> = 8 mA	4.5	_	_	0.36	_	0.44	
Input leakage current	I <sub>IN</sub>	_	V <sub>IN</sub> = 5.5 V or GND		0~ 5.5	_	_	±0.1	_	±1.0	μА
Quiescent supply current	Icc	_	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_	_	2.0	_	20.0	μА



## AC Characteristics (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics Symbol	Cumbal	Test	Т	Test Condition		Ta = 25°C			Ta = -40~85°C		Unit
	Circuit	<u> </u>	V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Тур.	Max	Min	Max	Offic	
Propagation delay time tpLH	·		_	3.3 ± 0.3	15		5.0	7.1	1.0	8.5	- ns
					50		7.5	10.6	1.0	12.0	
				5.0 ± 0.5	15	_	3.8	5.5	1.0	6.5	
					50	_	5.3	7.5	1.0	8.5	
Input capacitance	C <sub>IN</sub>	_		_			4	10	_	10	pF
Power dissipation capacitance	C <sub>PD</sub>	_			(Note)	_	13	_	_		pF

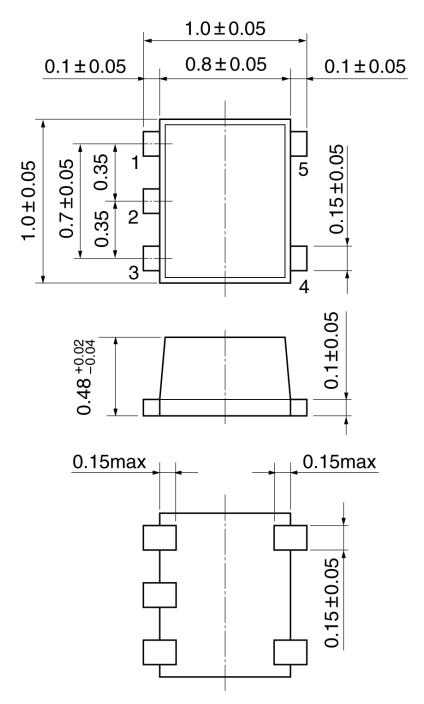
Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

## **Package Dimensions**

SON5-P-0.35 Unit:mm



Weight: 0.001 g (typ.)

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